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SPANSION PATENT RIGHTS

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FUJITSU PATENT APPLICATIONS AND ISSUED PATENTS

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
89P02073	H 1- 54998	19890309	19990319	SEMICONDUCTOR DEVICE	H 2-236178	2900941	19900919
93-07392	H 5-286658	19931116	20030411	CURRENT MIRROR TYPE OSCILLATOR CIRCUIT	H 7-142964	3418435	02.06.1995
93-07809	H 5-329285	19931227	20030320	FLASH MEMORY	H 7-192480	3409404	28.07.1995
94-00077	H 6-115360	19940527	20030404	SEMICONDUCTOR DEVICE	H 7-321207	3414496	08.12.1995
94-05461	H 6-168270	19940720	20030404	SEMICONDUCTOR MEMORY	H 8- 32437	3414852	02.02.1996
93-01191	H 5-152249	19930623	20040416	SEMICONDUCTOR STORAGE DEVICE	H 7- 21792	3545010	24.01.1995
93-08115	H 5-313341	19931214	2004.07.23	NON-VOLTAGE SEMICONDUCTOR MEMORY	H 7-169287	3578478	04.07.1995
93-09804	H 5-310244	19931210	2004.07.09	ELECTRICALLY ERASABLE NON-VOLATILE SEMICONDUCTOR MEMORY	H 7-169280	3573477	04.07.1995
93-12588	H 6- 48084	19940318	20040416	NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND DATA READING METHOD THEREOF	H 7-262787	3544222	13.10.1995
93-12603	H 6- 48116	19940318	2004.03.19	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE	H 7-263507	3534815	13.10.1995
93-14364	H 6-113271	19940527	2004.04.09	FLASH MEMORY	H 7-320492	3541427	08.12.1995
94-03231	H 6-220387	19940914	2004.09.24	SEMICONDUCTOR MEMORY DEVICE	H 8- 87898	3599793	02.04.1996
94-05460	H 7- 30629	19950220	2004.06.25	SEMICONDUCTOR MEMORY DEVICE	H 8-221998	3568265	30.08.1996
94-07025	H 7- 2771	19950111	2004.04.16	NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	H 8-195090	3544731	30.07.1996
94-11161	H 7-155664	19950622	2003.08.29	DATA OUTPUT CIRCUIT AND SEMICONDUCTOR MEMORY DEVICE	H 9- 8640	3465416	10.01.1997
94-11600	H 7-190846	19950726	2004.05.28	METHOD AND EQUIPMENT FOR TESTING NONVOLATILE MEMORY	H 9- 45100	3558746	14.02.1997
95-00231	H 7-173097	19950710	2004.04.09	SEMICONDUCTOR MEMORY	H 9- 27195	3541503	28.01.1997
96-04915	H 9- 66790	19970319		SEMICONDUCTOR DEVICE AND ITS MANUFACTURE	H10-261726		29.09.1998
97-00692	H 9-211663	19970806	2004.11.05	MANUFACTURE OF SEMICONDUCTOR DEVICE	H11- 54638	3613312	26.02.1999
97-03900	H10- 66888	19980317		MANUFACTURE OF SEMICONDUCTOR DEVICE	H11-265994		28.09.1999
99-40161	H11-226913	19990810		MULTI-BIT NON-VOLATILE MEMORY UTILIZING NON-CONDUCTIVE CHARGE TRAP GATE	2001- 57093		27.02.2001

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
99-40214	H11-334916	19991125		NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND ITS MANUFACTURING METHOD	2001-156272		08.06.2001
99-40253	H11-250780	19990903		SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURE THEREOF	2001- 77215		23.03.2001
99-40272	H11-294199	19991015		SEMICONDUCTOR MEMORY AND USAGE METHOD THEREFOR	2001-118940		27.04.2001
00-40262	2000-159102	20000529		SEMICONDUCTOR TESTER	2001-337128		07.12.2001
00-40755	2000-245859	20000814		METHOD FOR MANUFACTURING NONVOLATILE SEMICONDUCTOR MEMORY AND THE SAME MANUFACTURED THEREBY	2001-326288		22.11.2001
00-41159	2003-500918	20010525		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	WO02/09782 1		20021205
00-41238	2002-177482	20020618		METHOD AND DEVICE FOR READING DUAL BIT MEMORY CELL	2003- 68087		07.03.2003
01-40131	2003-131767	20030509		METHOD AND CIRCUIT FOR READING TWO BIT TYPE MEMORY CELL, AND SEMICONDUCTOR MEMORY DEVICE	2003-331592		21.11.2003
01-40674	2001-367052	20011130		SEMICONDUCTOR MEMORY AND ITS DRIVING METHOD	2003-173690		20.06.2003
01-41108	2002- 72350	20020315		SEMICONDUCTOR DEVICE	2003-270302		25.09.2003
01-41547	2002-319913	20021101		NONVOLATILE SEMICONDUCTOR MEMORY	2004-158052		03.06.2004
02-40035	2002-250932	20020829		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND DATA WRITING METHOD	2004-94987		25.03.2004
02-40036	2002-234857	20020812		VOLTAGE CONTROL CIRCUIT AND SEMICONDUCTOR MEMORY DEVICE	2004-79036		11.03.2004
02-40072	2003-122155	20030425		SYSTEM FOR CONTROLLING PRE- CHARGE LEVEL IN MEMORY DEVICE	2003-323796		14.11.2003
02-40253	2002- 80554	20020322		SEMICONDUCTOR MEMORY DEVICE	2003-281896		03.10.2003
02-40254	2002-234463	20020812		NONVOLATILE MEMORY HAVING TRAP LAYER	2004-79602		11.03.2004
02-40562	2002-319914	20021101		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-158053		03.06.2004
02-40878	2002-313954	20021029		SEMICONDUCTOR INTEGRATED CIRCUIT	2004-152341		27.05.2004
02-41001	2003- 9355	20030117		NONVOLATILE MULTI- LEVEL SEMICONDUCTOR MEMORY	2004-220728		05.08.2004

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
02-41003	2003- 39689	20030218		NONVOLATILE SEMICONDUCTOR MEMORY	2004-253021		09.09.2004
02-41118	2003- 17466	20030127		SEMICONDUCTOR STORAGE DEVICE EQUIPPED WITH HIGH SPEED READOUT CIRCUIT	2004-227486		12.08.2004
02-41195	2002-269838	20020917		OPTICAL RECORDING MEDIUM FOR INSPECTION, METHOD FOR MANUFACTURING OPTICAL RECORDING MEDIUM FOR INSPECTION AND DISK DRIVE INSPECTION METHOD	2002-269838		20.09.2002
02-41217	2002-265065	20020911		MEMORY CIRCUIT HAVING REDUNDANCY CONSTITUTION	2004-103143		02.04.2004
02-41218	2002-268316	20020913		METHOD FOR DESIGNING SEMICONDUCTOR MEMORY DEVICE, AND SEMICONDUCTOR MEMORY DEVICE	2004-111443		08.04.2004
02-41219	2002-267097	20020912		SEMICONDUCTOR NONVOLATILE MEMORY WHICH HAS IMPROVED TRACKING CHARACTERISTIC	2004-103181		02.04.2004
02-41222	2002-268643	20020913		NONVOLATILE MEMORY CIRCUIT AND NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-110883		08.04.2004
02-41532	2003- 38636	20030217		STEP-UP CIRCUIT OF SMALL AREA WITH MULTISTAGE STRUCTURE	2004-247689		02.09.2004
02-41534	2003- 38642	20030217		CHARGE PUMP CIRCUIT WITH REDUCED AMPLITUDE OF STEP-UP VOLTAGE	2004-248475		02.09.2004
02-41535	2003- 73287	20030318		NONVOLATILE SEMICONDUCTOR MEMORY AND ITS OPERATION CONTROL METHOD	2004-280981		07.10.2004
02-41634	2002-370272	20021220		CONTROL METHOD OF NONVOLATILE SEMICONDUCTOR STORAGE DEVICE, AND NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-199833		15.07.2004
02-41637	2002-370273	20021220		METHOD OF CONTROLLING SEMICONDUCTOR DEVICE, AND THE SEMICONDUCTOR DEVICE	2004-199600		15.07.2004
02-41643	2002-370275	20021220		SEMICONDUCTOR DEVICE, SEMICONDUCTOR STORAGE DEVICE, AND TEST METHOD THEREFOR	2004-199834		15.07.2004
02-41644	2002-370276	20021220		SEMICONDUCTOR STORAGE DEVICE AND	2004-199835		15.07.2004

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
				TEST METHOD THEREFOR			
02-41660	2002-348485	20021129		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND SEMICONDUCTOR DEVICE	2004-185670		02.07.2004
02-41661	2002-342677	20021126		SEMICONDUCTOR DEVICE AND ITS TESTING METHOD	2004-178672		24.06.2004
02-41696	2002-371126	20021220		SEMICONDUCTOR MEMORY DEVICE AND ITS CONTROL METHOD	2004-206740		22.07.2004
02-41698	2002-370277	20021220		CONTROL METHOD OF NONVOLATILE MEMORY, AND NONVOLATILE MEMORY	2004-199836		15.07.2004
02-41702	2003- 76960	20030320		SEMICONDUCTOR MEMORY DEVICE	2004-288260		14.10.2004
02-41719	2003- 87868	20030327		CHARGING PUMP CIRCUIT	2004-297922		21.10.2004
02-41730	2002-369554	20021220		SEMICONDUCTOR STORAGE DEVICE AND ITS CONTROL METHOD	2004-199825		15.07.2004
03-40053	PCT	20030428					
03-40222	2003-136269	20030514		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND METHOD FOR DETERMINING DATA	2004-047050		12.02.2004
99-40337	H11-293027	19991014		NON-VOLATILE MEMORY CIRCUIT RECORDING MULTI-BIT INFORMATION	2001-118390		27.04.2001
00-40018	2002-518468	20000803			WO02/01319 9		14.02.2002
00-40619	2002-551860	20001221		NONVOLATILE SEMICONDUCTOR MEMORY AND METHOD OF ERASURE	WO2002/050 843		20020627
00-40996	2001-123180	20010420		NONVOLATILE SEMICONDUCTOR MEMORY	2002-319287		31.10.2002
01-40129	2003-114392	20030418		METHOD AND SYSTEM FOR PROGRAMMING THRESHOLD VOLTAGE LEVEL AND SEMICONDUCTOR STORAGE DEVICE	2003-323793		14.11.2003
01-40756	2001-252400	20010823		MEMORY CONTROLLER FOR MULTI-VALUE CELL MEMORY	2003- 67260		07.03.2003
01-41067	2003- 51449	20030227		SYSTEM FOR SETTING MEMORY VOLTAGE THRESHOLD	2003-263895		19.09.2003
01-41415	2002-114145	20020417		NONVOLATILE SEMICONDUCTOR MEMORY AND METHOD OF MANUFACTURING THE SAME	2003-309192		31.10.2003
01-41516	2002- 53994	20020228		NONVOLATILE SEMICONDUCTOR MEMORY DEVICE	2003-257188		12.09.2003

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
02-40420	2003-159556	20030604		NONVOLATILE SEMICONDUCTOR MEMORY	2004-273093		30.09.2004
02-41214	2002-268606	20020913		SEMICONDUCTOR MEMORY	2004-110881		08.04.2004
02-41221	2002-268317	20020913		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-110872		08.04.2004
98-40297	H11-209787	19990723		NON-VOLATILE MEMORY ENABLING ENCRPTION OF COMMAND	2001- 35171		09.02.2001
99-40506	2001-560823	20000216		NONVOLATILE MEMORY	2001- 861503 (WO 01/061503)		20010823
00-40048	2002-505627	20000629		SEMICONDUCTOR MEMORY DEVICE	WO02/001574		20020103
01-40842	2002- 12985	20020122		SEMICONDUCTOR NONVOLATILE MEMORY WITH FRAUDULENT READING PREVENTING FEATURE	2003-216499		31.07.2003
01-40865	2002- 45116	20020221		ERROR DETECTING/CORRECTING METHOD FOR MULTI-LEVEL SEMICONDUCTOR MEMORY, AND MULTI-LEVEL SEMICONDUCTOR MEMORY HAVING ERROR DETECTING/CORRECTING FUNCTION	2003- 36693		07.02.2003
01-41056	2001-322813	20011019		NONVOLATILE SEMICONDUCTOR MEMORY AND CONTROL METHOD THEREFOR	2003-132688		09.05.2003
01-41288	2002-120548	20020423		LOW TEMPERATURE TEST APPARATUS FOR SEMICONDUCTOR DEVICE USING ELECTRONIC COOLING ELEMENT	2003-315406		06.11.2003
01-41306	2002- 4150	20020111		MEMORY DEVICE	2002-328836		15.11.2002
02-40528	2002-231825	20020808		METHOD FOR CONTROLLING SEMICONDUCTOR MEMORY DEVICE AND SEMICONDUCTOR MEMORY DEVICE	2004-71105		04.03.2004
02-41215	2002-268315	20020913		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-110871		08.04.2004
02-41410	PCT/JP2003/ 001971	20030224		VOLTAGE SENSING CIRCUIT, SEMICONDUCTOR DEVICE, METHOD FOR CONTROLLING VOLTAGE SENSING CIRCUIT	WO20040752 02		20040902

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
02-41434	PCT/JP2003/001739	20030218		SEMICONDUCTOR5 STORAGE DEVICE AND SEMICONDUCTOR STORAGE DEVICE READ OUT METHOD	WO2004075199		20040902
02-41531	2004-568757	20030227					
02-41615	2004-568776	20030228					
02-41642	2002-370274	20021220		SEMICONDUCTOR DEVICE AND ITS TESTING METHOD	2004-198367		15.07.2004
02-41651	2005-500549	20030605					
02-41655	2005-500550	20030605					
02-41656	2004-571303	20030430					
02-41690	2004-569330	20030311					
02-41701	2002-370278	20021220		NONVOLATILE MEMORY AND WRITING METHOD THEREFOR	2004-199837		15.07.2004
02-41729	2002-377039	20021226		SEMICONDUCTOR MEMORY AND CONTROL METHOD FOR SEMICONDUCTOR MEMORY	2004-206832		22.07.2004
02-41828	2002-374366	20021225		STORAGE METHOD AND STORAGE DEVICE FOR NONVOLATILE MEMORY	2004-206381		22.07.2004
03-40052	2003- 50264	20030227		SEMICONDUCTOR MEMORY DEVICE	2004-259385		16.09.2004
03-40067	PCT	20030424					
03-40184	PCT	20030417					
03-40729	2005-500563	20030605					
91P08819	1991-240040(H03)	19910919	26.09.2003	SEMICONDUCTOR MEMORY	H05-81887	3476479	02.04.1993
99-40900	JP2000/004801	20000717		SYSTEM FOR UTILIZING DYNAMIC REFERENCE BY TWO-BIT CELL MEMORY	WO2002007215		
01-41290	2003-274071	20030714		SYSTEM FOR UTILIZING DYNAMIC REFERENCE BY TWO-BIT CELL MEMORY	2004-039234		05.02.2004
02-41032	2002-267680	20020913		SEMICONDUCTOR MEMORY FOR NORMALLY PERFORMING REPLACEMENT WITH REDUNDANCY CELL ARRAY	2004-110861		08.04.2004
02-40906	2003-380841	Outsource d 14.08.05 20031111 Priority Date 20030606)		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-362729		24.12.2004

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
00-40183	2000-141072	20000515		NON-VOLATILE SEMICONDUCTOR MEMORY, AND DATA HOLDING METHOD FOR NON-VOLATILE SEMICONDUCTOR MEMORY	2001-325793		22.11.2001
99-40134	H11-300401	19991022	2003.05.16	NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2001-118943	3430084	
91P10042	H03-279308	19911025		NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND MANUFACTURE THEREOF	H05-121702		
99-40225	H11-266074	19990920		SEMICONDUCTOR INTEGRATED-CIRCUIT DEVICE AND MANUFACTURING METHOD THEREOF	2001-094076		
98-02045	H10-345307	19981204		MANUFACTURE OF SEMICONDUCTOR DEVICE	2000-174235		
99-40258	H11-266075	19990920	2004.01.16	NONVOLATILE SEMICONDUCTOR STORAGE, WRITING METHOD AND READING METHOD THEREFOR	2001-093995	3513056	
00-41250	2001-076585	20010316		SEMICONDUCTOR DEVICE AND ITS FABRICATING METHOD	2002-280464		
01-40212	2001-094582	20010329		SEMICONDUCTOR MEMORY AND ITS DRIVING METHOD	2002-299473		
97-01109	H09-184773	19970710		NON-VOLATILE SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF	H11-031798		
97-05686	H10-066898	19980317		SEMICONDUCTOR DEVICE AND ITS MANUFACTURE	H11-265947		
97-07264	H10-128682	19980512		MANUFACTURE OF SEMICONDUCTOR DEVICE	H11-330274		
02-41423	2003-030977	20030207		NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND ITS MANUFACTURING METHOD	2004-241698		
91P10155	H03-277488	19911024	2003.06.27	TEST METHOD FOR SEMICONDUCTOR DEVICE	1993120900	3444902	
98-01577	H10-308082	19981029		MANUFACTURE OF SEMICONDUCTOR STORAGE DEVICE	2000-133727		
98-02046	H10-349028	19981208		SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURE THEREOF	2000-174237		
00-40023	2000-209230	20000711		SEMICONDUCTOR STORAGE DEVICE AND ITS MANUFACTURING METHOD	2002-026155		

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
00-40405	2000-276398	20000912		SEMICONDUCTOR STORAGE DEVICE AND ITS CONTROL METHOD	2002-093925		
94-03318	H06-223270	19940919		FLASH MEMORY AND MANUFACTURE THEREOF	H08-088287		
02-40764	2002-266995	20020912		SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF	2004-104009		
02-50911	2002-230062	20020807		SEMICONDUCTOR STORAGE DEVICE AND ITS MANUFACTURING METHOD	2004-071877		
02-41448	2003-027514	20030204		SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURING METHOD THEREOF	2004-241503		
02-41913	2003-104841	20030409		MANUFACTURING METHOD OF SEMICONDUCTOR STORAGE DEVICE	2004-311803		
02-41452	2003-060360	20030306		MANUFACTURING METHOD OF SEMICONDUCTOR STORAGE DEVICE	2004-273643		
01-40603	2001-260702	20010830		STATIC RANDOM ACCESS MEMORY WITH NON-VOLATILE DATA HOLDING FUNCTION AND ITS OPERATING METHOD	2003-068982		
02-40033	2002-135688	20020510		NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2003-332469		
00-41147	2000-351444	20001117		NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND MANUFACTURING METHOD THEREOF	2002-158298		
00-41153	2001-031320	20010207		SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME	2002-237540		
97-7547	1997-350393 (H09)	19971219	2003.12.12	MANUFACTURE OF SEMICONDUCTOR DEVICE	1999186261	3500564	
90P10187	1990-279832 (H02)	19901018	1997.04.25	MANUFACTURE OF SEMICONDUCTOR DEVICE	1992154124	2639202	
96-07070	H08-318130	19961128	2003.06.20	MANUFACTURE OF SEMICONDUCTOR DEVICE	H10-163456	3442596	
02-41600	2002-354049	20021205	-	NONVOLATILE SEMICONDUCTOR MEMORY	2004-158810	-	
91P07591	H03-201033	19910812	1997.11.21	MANUFACTURE OF SEMICODUCTOR DEVICE	H05-048046	2720645	
02-40107	2002-146184	20020521	-	NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2003-338566	-	

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
02-40193	2002-255919	20020830	-	METHOD FOR MANUFACTURING MEMORY INTEGRATED CIRCUIT DEVICE	2004-095904	-	2005.08.25
02-41716	2003-132041	20030509	-	NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2004-056095	-	
05-80085	2005- 96274	20050329		SEMICONDUCTOR DEVICE	2005-229128		